

**Search Notes**

Application/Control No.

10/526,940

Examiner

Karen Cheng

Applicant(s)/Patent under  
Reexamination

DEUSCHLE ET AL.

Art Unit

1626

**SEARCHED**

Class	Subclass	Date	Examiner
548	373.1	3/8/2007	KC
548	377.1	3/8/2007	KC
514	406	3/8/2007	KC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STN Structure Search (see attached)	3/1/2007	KC
Inventor name Search (PALM)	3/7/2007	KC
EAST Search (see attached)	3/8/2007	KC